

# FAST 74F1244 Buffer

## FAST Products

## 74F1244 Octal Buffer (3-State)

### FEATURES

- High impedance NPN base inputs for reduced loading ( $20\mu\text{A}$  in High and Low states)
- Low power, light loading
- Functional pin for pin equivalent of 'F244
- 1/30th the bus loading of 'F244
- Provides ideal interface and increase fan-out of MOS Microprocessors
- Octal bus interface
- 3-State buffer outputs sink 64mA and source 15mA

### Product Specification

TYPE	TYPICAL PROPAGATION DELAY	TYPICAL SUPPLY CURRENT (TOTAL)
74F1244	4.5ns	43mA

### ORDERING INFORMATION

PACKAGES	COMMERCIAL RANGE $V_{CC} = 5V \pm 10\%$ ; $T_A = 0^\circ\text{C}$ to $+70^\circ\text{C}$
20-Pin Plastic DIP	N74F1244N
20-Pin Plastic SOL	N74F1244D

### DESCRIPTION

The 74F1244 is an octal buffer that is ideal for driving bus lines or buffer memory address registers. The outputs are capable of sinking 64mA and sourcing up to 15mA, producing very good capacitive drive characteristics. The device features two Output Enables,  $\overline{OE}_a$  and  $\overline{OE}_b$ , each controlling four of the 3-state outputs.

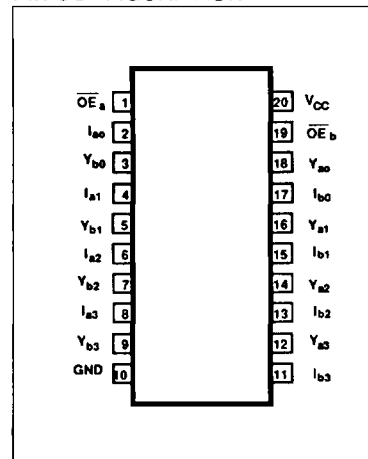
The 'F1244 is pin and functional compatible with the 'F244. The lower power and light bus loading features make it an ideal part to interface directly with MOS Microprocessors.

### INPUT AND OUTPUT LOADING AND FAN-OUT TABLE

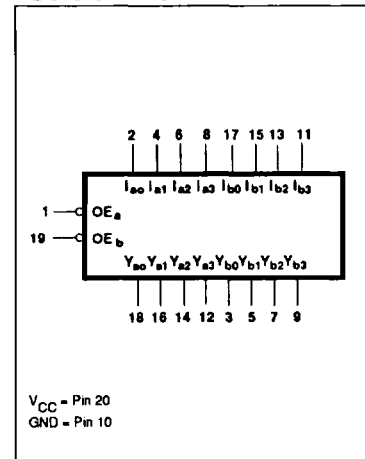
PINS	DESCRIPTION	74F(U.L.) HIGH/LOW	LOAD VALUE HIGH/LOW
$I_{an}, I_{bn}$	Data inputs	1.0/0.033	$20\mu\text{A}/20\mu\text{A}$
$\overline{OE}_a, \overline{OE}_b$	Output Enable inputs (active Low)	1.0/0.033	$20\mu\text{A}/20\mu\text{A}$
$Y_{an}, Y_{bn}$	Data outputs	750/106.7	15mA/64mA

NOTE:  
One (1.0) FAST Unit Load is defined as:  $20\mu\text{A}$  in the High state and 0.6mA in the Low state.

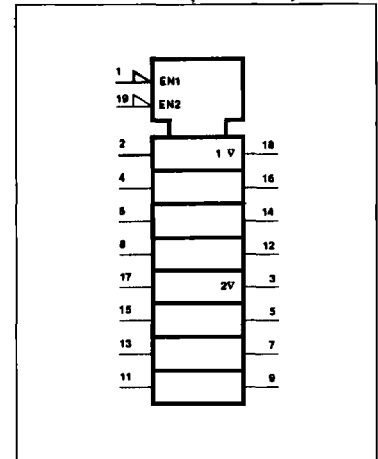
### PIN CONFIGURATION



### LOGIC SYMBOL



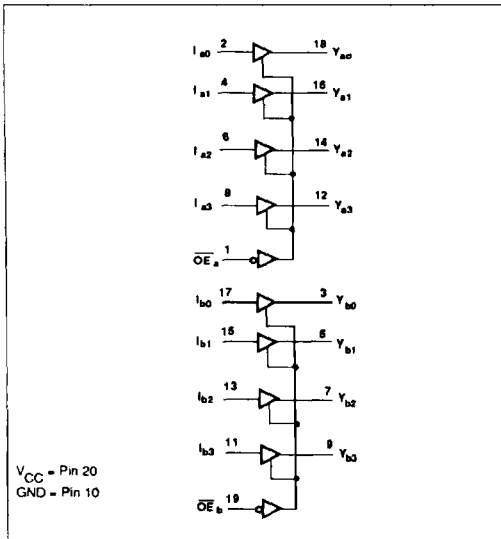
### LOGIC SYMBOL (IEEE/IEC)



Buffer

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LOGIC DIAGRAM



FUNCTION TABLE

INPUTS				OUTPUTS	
$\overline{OE}_a$	$I_a$	$\overline{OE}_b$	$I_b$	$Y_a$	$Y_b$
L	L	L	L	L	L
L	H	L	H	H	H
H	X	H	X	Z	Z

- H = High voltage level
- L = Low voltage level
- X = Don't care
- Z = High impedance "off" state

**ABSOLUTE MAXIMUM RATINGS** (Operation beyond the limits set forth in this table may impair the useful life of the device. Unless otherwise noted these limits are over the operating free-air temperature range.)

SYMBOL	PARAMETER	RATING	UNIT
$V_{CC}$	Supply voltage	-0.5 to +7.0	V
$V_{IN}$	Input voltage	-0.5 to +7.0	V
$I_{IN}$	Input current	-30 to +5	mA
$V_{OUT}$	Voltage applied to output in High output state	-0.5 to + $V_{CC}$	V
$I_{OUT}$	Current applied to output in Low output state	128	mA
$T_A$	Operating free-air temperature range	0 to +70	°C
$T_{STG}$	Storage temperature	-65 to +150	°C

**RECOMMENDED OPERATING CONDITIONS**

SYMBOL	PARAMETER	LIMITS			UNIT
		Min	Nom	Max	
$V_{CC}$	Supply voltage	4.5	5.0	5.5	V
$V_{IH}$	High-level input voltage	2.0			V
$V_{IL}$	Low-level input voltage			0.8	V
$I_{IK}$	Input clamp current			-18	mA
$I_{OH}$	High-level output current			-15	mA
$I_{OL}$	Low-level output current			64	mA
$T_A$	Operating free-air temperature range	0		70	°C

## Buffer

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**DC ELECTRICAL CHARACTERISTICS** (Over recommended operating free-air temperature range unless otherwise noted.)

SYMBOL	PARAMETER	TEST CONDITIONS <sup>1</sup>			LIMITS			UNIT	
					Min	Typ <sup>2</sup>	Max		
$V_{OH}$	High-level output voltage	$V_{CC} = \text{MIN},$ $V_{IL} = \text{MAX}$ $V_{IH} = \text{MIN},$	$I_{OH} = -3\text{mA}$	$\pm 10\%V_{CC}$	2.5			V	
				$\pm 5\%V_{CC}$	2.7	3.4		V	
			$I_{OH} = -15\text{mA}$	$\pm 10\%V_{CC}$	2.0			V	
				$\pm 5\%V_{CC}$	2.0			V	
$V_{OL}$	Low-level output voltage	$V_{CC} = \text{MIN},$ $V_{IL} = \text{MAX}$ $V_{IH} = \text{MIN},$	$I_{OL} = 48\text{mA}$	$\pm 10\%V_{CC}$		0.38	0.55	V	
			$I_{OL} = 64\text{mA}$	$\pm 5\%V_{CC}$		0.42	0.55	V	
$V_{IK}$	Input clamp voltage	$V_{CC} = \text{MIN}, I_I = I_{IK}$				-0.73	-1.2	V	
$I_I$	Input current at maximum input voltage	$V_{CC} = 0.0\text{V}, V_I = 7.0\text{V}$					100	$\mu\text{A}$	
$I_{IH}$	High-level input current	$V_{CC} = \text{MAX}, V_I = 2.7\text{V}$					20	$\mu\text{A}$	
$I_{IL}$	Low-level input current	$V_{CC} = \text{MAX}, V_I = 0.5\text{V}$					-20	$\mu\text{A}$	
$I_{OZH}$	Off-state output current, High-level voltage applied	$V_{CC} = \text{MAX}, V_O = 2.7\text{V}$					50	$\mu\text{A}$	
$I_{OZL}$	Off-state output current, Low-level voltage applied	$V_{CC} = \text{MAX}, V_O = 0.5\text{V}$					-50	$\mu\text{A}$	
$I_{OS}$	Short-circuit output current <sup>3</sup>	$V_{CC} = \text{MAX}$			-100		-225	mA	
$I_{CC}$	Supply current (total)	$I_{CCH}$	$V_{CC} = \text{MAX}$				30	40	mA
		$I_{CCL}$					57	75	mA
		$I_{CCZ}$					43	58	mA

**NOTES:**

- For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions for the applicable type.
- All typical values are at  $V_{CC} = 5\text{V}, T_A = 25^\circ\text{C}$ .
- Not more than one output should be shorted at a time. For testing  $I_{OS}$ , the use of high-speed test apparatus and/or sample-and-hold techniques are preferable in order to minimize internal heating and more accurately reflect operational values. Otherwise, prolonged shorting of a High output may raise the chip temperature well above normal and thereby cause invalid readings in other parameter tests. In any sequence of parameter tests,  $I_{OS}$  tests should be performed last.

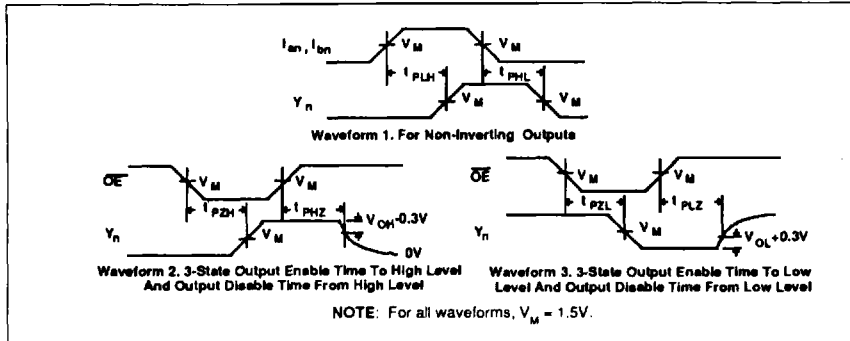
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AC ELECTRICAL CHARACTERISTICS

SYMBOL	PARAMETER	TEST CONDITION	LIMITS					UNIT
			$T_A = +25^\circ\text{C}$ $V_{CC} = 5\text{V}$ $C_L = 50\text{pF}$ $R_L = 500\Omega$			$T_A = 0^\circ\text{C to } +70^\circ\text{C}$ $V_{CC} = 5\text{V} \pm 10\%$ $C_L = 50\text{pF}$ $R_L = 500\Omega$		
			Min	Typ	Max	Min	Max	
$t_{PLH}$	Propagation delay	Waveform 1	2.5	4.0	5.5	2.5	6.0	ns
$t_{PHL}$	$I_{an}, I_{bn}$ to $Y_n$		2.0	5.0	7.0	2.0	7.5	ns
$t_{PZH}$	Output Enable time to High or Low level	Waveform 2	3.0	6.0	7.5	3.0	8.5	ns
$t_{PZL}$		Waveform 3	3.0	6.5	8.0	3.0	8.5	ns
$t_{PHZ}$	Output Disable time to High or Low level	Waveform 2	2.0	4.0	5.5	2.0	6.0	ns
$t_{PLZ}$		Waveform 3	2.0	4.0	5.5	2.0	6.0	ns

AC WAVEFORMS



TEST CIRCUIT AND WAVEFORMS

Test Circuit For 3-State Outputs

TEST	SWITCH
$t_{PLZ}$	closed
$t_{PZL}$	closed
All other	open

DEFINITIONS

$R_L$  = Load resistor; see AC CHARACTERISTICS for value.

$C_L$  = Load capacitance includes jig and probe capacitance; see AC CHARACTERISTICS for value.

$R_T$  = Termination resistance should be equal to  $Z_{OUT}$  of pulse generators.

$V_M = 1.5\text{V}$   
Input Pulse Definition

FAMILY	INPUT PULSE REQUIREMENTS				
	Amplitude	Rep. Rate	$t_W$	$t_{TLH}$	$t_{THL}$
74F	3.0V	1MHz	500ns	2.5ns	2.5ns